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"DEVELOPMENT OF RECONFIGURABLE AUTOMATED VISUAL INSPECTION SYSTEMS"

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Agenda



Introduction

- **Problem Context**
- Envisioned Reconfigurable Environment
 - **Modules Description**
 - General Overview of Reconfiguration Methodology
 - Conclusion



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Feature Definition



- A feature in our context is usually a prominent or distinctive characteristic that can be extracted from a digital image of an SMD component.
- Each feature acts as a function whose domain is the digital image and whose range is the real line.
- In our case we have six features: Energy (E), Correlation (C), Diffusion (D), Fenergy (F), Blob (B) and Texture (T).





Problem Statement



 The lack of flexibility, combined with the rapid introduction and retirement of electronic products, has deterred equipment manufacturers and the electronic assembly industry from investing in the development of AVI systems more convenient for process improvement.

- It is necessary to build AVI systems that are more easily adaptable to new electronic products.
 - AVI Systems should not be rendered obsolete by minimum changes in component technology or change of product designs.



Envisioned Reconfigurable Environment



- In order to achieve the objective of developing selfreconfigurable AVI systems we need to decompose the overall problem into simpler sub-problems. The modules of this reconfigurable environment are:
- 1. An Automated Feature Generation and Optimization Module
- 2. A Decision Module
- **3.** A Feature Selection Module
- 4. An Inspection Performance Assessment Module
- 5. An Inspection Refinement Module





The objective of this module is to generate without (or minimal) human intervention the features to be used to inspect the new component/product.

Once that the potential inspection features have been generated; the next step is to optimize them to render the best individual discrimination possible.



1.1 Feature Generation



- We are planning to start from traditional approaches for feature generation by basing our development on features that have:
 - Common characteristics
 - Computationally inexpensive and simple enough to accommodate new components by just changing their parameters.





1.2 Individual Feature Parameters Optimization



- The objective is to set the parameters of each feature independently such that the discrimination between the defective and non-defective populations is maximized.
- We will explore a heuristic-iterative approach to search for good levels of discrimination between the populations.



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2. Decision Module



The objective is to have a classifier easy to use with a great power of discrimination between the populations.

The characteristics should be

 Easily expandable and changeable to include other features in addition to the pre-existing ones.

✓The robustness of the features used in the classifier.



2.2 Quadratic Classification Function





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Analytical determination of the minimum number of training sample required to ensure statistical reliability in the parameter estimation.

Some of the approaches are,

- Specify the desired width of a confidence interval and determine the sample size that achieves that goal.
- Bayesian approach can be used where we optimize some utility function.
- Another approach involving the power of a test of hypothesis.



3. Feature Selection Module

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The goal of this module is to automatically select a subset of features among the larger set of features known to provide the greatest level of discrimination.

The problem of feature selection is as follows:

"Given a set of *p* features, select a subset of size *m* that leads to the smallest classification error; given the existing time constraints".



Example of Feature Selection



Rank	Features	MER
1	Correlation	0.0125
2	Diffusion	0.0196
3	Energy	0.0392
4	Fenergy	0.0819
5	Texture	0.2847
6	Blob	0.3719

Table - MER for each Feature

Features	Energy	Correlation	Diffusion	Fenergy	Blob	Texture
Energy	1.00	0.84	0.90	0.83	0.52	0.50
Correlation	0.84	1.00	0.93	0.82	0.42	0.53
Diffusion	0.90	0.93	1.00	0.83	0.49	0.55
Fenergy	0.83	0.82	0.83	1.00	0.33	0.53
Blob	0.52	0.42	0.49	0.33	1.00	0.27
Texture	0.50	0.53	0.55	0.53	0.27	1.00

Table - Cross-Correlation between Features



Stepwise Discriminant Analysis (SDA)





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4. Inspection Performance Assessment Module



Although it is relatively "easy" to measure current performance, projections of future performance become more complex and less reliable if the populations are no stable.



Contours of Joint Features

Joint Features

4.1 Classifier Performance Measurements



- We use three non-parametric statistics that measure the level of discrimination through the Misclassification Error Rate (MER). These methods are:
 - The APER is a biased estimator of the probability of errors as it is evaluated on the training data.
 - The EAER is a nearly unbiased estimate of the expected true error rate of the population (this statistic is calculated using cross-validation of size one).
 - The IER is an unbiased estimator of the true error rate because the used data is independent from the training data utilized to build the QCF.







- Regression Analysis is used to predict the AVI performance.
- The dependent variable of the equation is the MER.
- It is necessary to determine the independent variable. We have explored methods such as
 - -Wilks' Lambda Value,
 - —Hotelling-Lawley Trace Value
 - -Statistical Distance between Populations D_{A-P}



4.2.1 Wilks' Lambda Value



This is a measure of the difference between populations of the centroid (vector) of means on the independent variables.

The smaller the value of lambda, the greater the difference between the populations.

► The likelihood ratio test statistics can be expressed as; $\Lambda = \frac{|\mathbf{W}|}{|\mathbf{B} + \mathbf{W}|} = \prod_{i=1}^{s} \frac{1}{1 + \lambda_i}$



Experimental Results

241
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Statistics	MER	Wilks	Hotelling	D ₁₋₂
MER	1.000	0.953	-0.739	-0.745
Wilks	0.953	1.000	-0.894	-0.901
Hotelling	-0.739	-0.894	1.000	0.983
D _{A-P}	-0.745	-0.901	0.983	1.000



	Jothod	Regress	ion Analys is	Mc	delAdequ	Analysis of Variance			
		Constant Coefficient		R²	PRESS	R ³ prediction	F Value	P Value	
	Wilks	-0.081	0.473	0.91	0.031	0.874	615.77	0	
E	Iotelling	0 172	-0.038	0.55	Q 137	0,439	73.43	0	
	D ₁₋₂	Q 186	-0.017	0.55	Q 137	Q.439	76 17	0	





- The objective is to continuously improve the performance of the AVI system.
- This module includes a methodology for;
 Eliminating the Noise present in the training data.
 - -Joint Optimization of the parameters of the features used in the inspection.
 - -Constructing New Features based on the current performance of the system.





• The second step of the methodology is the creation of the function to identify the outliers.

- Some of the methods that we will explore to create the function to eliminate outliers are based on the
 - -Classification Boundary
 - -Chi-Square Distribution
 - -Mahalanobis Distance





 This measure standardizes the distance between two vectors with the inverse of the covariance matrix:

$$T^{2} = n(\overline{\mathbf{x}} - \boldsymbol{\mu}_{0})'\mathbf{S}^{-1}(\overline{\mathbf{x}} - \boldsymbol{\mu}_{0})$$

 This test can be used to determine which elements can be classified as outliers.

$$T_{Pi}^{2} = \left(\overline{\mathbf{x}}_{P} - \mathbf{x}_{i}\right)' \mathbf{S}_{P}^{-1} \left(\overline{\mathbf{x}}_{P} - \mathbf{x}_{i}\right)$$
$$T_{Ai}^{2} = \left(\overline{\mathbf{x}}_{A} - \mathbf{x}_{i}\right)' \mathbf{S}_{A}^{-1} \left(\overline{\mathbf{x}}_{A} - \mathbf{x}_{i}\right)$$

• If T_{Pi}^2 or $T_{Ai}^2 \ge T_{\alpha,p,n-1}^2$, the element *i* is considered as an outlier.



Experimental Results



SCENARIOS	Inspection Data With Outliers	Inspection Data With Outliers	Inspection Data Without Outliers	
Training Data With Outliers	Α			
Training Data Without Outliers		В	С	

Scenarious	A			В				С			
Features	Bements	MER	Value	Bements	Method	MER	Value	Elements	Method	MER	Value
	281	APER	0.0198	281	D⊨∧ <u>8</u>	APER	0.0000	281	Dp.A	APER	0
	281	EAER	0.0198	281		EAER	0.0000	261		EAER	0
	2810	IER	0.0178	2810		IER	0.0224	2810		Ē	0
				283	263		0.0019	263		APBR	0.0019
ECDFBT				263	Hotelling's T ²	EAER	0.0038	283	Hotelling's T ²	EAER	0.0038
				2810	810		0.0178	2630		Ē	0.0096
				281		APER	0.0019	281	CHI-SQUARE	APER	0.0019
				281	CHI-SQUARE	EAER	0.0038	281		EAER	0.0038
				2810		IER	0.0176	2810		B	0.0036



5.2 Multi-Feature Parameters Re-Optimization



- Optimizing a single parameter might not result in the global maximization of that feature's response.
- The approach is based on factorial design and multiple response surface methodologies.





5.3 Feature Construction



- Feature construction is a process that discovers missing information about the relationships between features and augments the space of features by inferring or creating additional features.
- For example, assuming there are n original features A₁, A₂,..., A_n", after feature construction, we may have the additional m features A_{n+1}, A_{n+2}, ..., A_{n+m}.
- > Another example: a two-dimensional problem (say, A_1 =width and A_2 =length) may be transformed into a one-dimensional problem (B_1 = area) after B_1 is constructed.





- 1. Create features for the AVI system.
- 2. Optimize the features independently.
- 3. Determine the training sample size.
- 4. Obtain images with defective and non-defective components.
- 5. Apply the predefined features to the images to obtain the multivariate information.
- 6. Based on the multivariate information, estimate the parameters for the defective and non-defective global populations.
- 7. Determine the best subset of features for each component.
- 8. Estimate the AVI performance in the training stage and for the functioning in the factory floor.





9.Create new features to improve the classification for those components whose performance values are outside the acceptable level of discrimination.

- 10.Determine the clusters of components and eliminate the outliers from them.
- 11.Optimize the parameters jointly for each subset of features.
- 12.Identify those components for which, given the current set of features, neither global nor local classification is possible. Term these components special cases.
- 13.Create additional features for the classification of special cases.



Conclusion



- The resulting development framework will
 - Significantly shorten the development time for inspection algorithms.
 - Minimize the intervention of human developers.
 - Improve the AVI systems in two dimensions of flexibility;
 - Introduction of new products and
 - Rapid product changeovers.
- While the envisioned resulting methodology will be of immediate application in the electronics assembly industry, its impact goes beyond of this application.
 - Medical Diagnostic
 - Solder Paste Inspection
 - Inspection of Textile Products

